CMS ECAL VFE phase II upgrade workshop CEA-Saclay INSTN 11-13 May 2016

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TESTS OF DC-DC CONVERTERS

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OUTLINE

Introduction

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- LHC and HL-LHC
- CMS and ECAL Phase II barrel upgrades
- Preliminary test of DC-DC converters @UVa
- UVa's future plans and status of the art
- Conclusions







LHC AND HL-LHC

	LHC	HL-LHC
Instantaneous luminosity [cm ² s ⁻¹]	10 ³⁴	7x10 ³⁴
Number of events per BC at 25 ns	28	≈ 200
Number of events per BC at 50 ns	56	≈ 400
Integrated luminosity [fb ^{.1}]	300	3000
Integrated luminosity [fb ^{.1}]	300	3000

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CMS is planning significant upgrades for Phase II

Motivations:

- Radiation resistance: replace components with more radiation-tolerance to sustain 3000 fb⁻¹
- Ageing: some components would have ~30 yrs operation, difficult to maintain and repair
- Provide highest granularity information and resolution: efficient and selective triggers at high lumi

ECAL PHASE II BARREL UPGRADES

- Remove all 36 super-modules, replace FE cards + services (power, electrical signals, opto-links, cooling)
 - Decrease volume of services on YBO in order to make the re-cabling easier → E.g. by decreasing the LV current to the EB Front End by using DC-DC converters on the LVRB (switching sLVRB= Low Voltage Regulator Board) thus using less cables

• New FE card:

- Remove all L1 crystal sums, remove buffer, send all data out @40 MHz (TRIGGER)
- CERN GBTx/Versatile link for data transfer to back-end and control
- will need 10 Gbps rad-tolerant link

• New VFE card:

• Change preamp shaper, ADC

• New back-end:

 Evolution of MP7 μTCA board as developed for Phase I Trigger based on FPGA Xilink Virtex 7



SLVR CARD

- SLVR card hosts 6 FEASTMP modules. Voltages and currents are monitored via 3 DCU ASICS
- Testing the card concerns:

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- Testing the proper functioning of the installed FEASTMP modules and of the DCUs in the assembled card
- The performance of the card as part of the detector front-end readout system has to be evaluated/repeated with every version of the front-end electronics
- Reliability and safe operation: card is installed inside the ECAL barrel super modules and maintenance during the life-cycle planned for the detector is excluded









ELECTRICAL CHARACTERIZATION

ELECTRICAL CHARACTERIZATION:

• Output voltage:

measure the value

measure stability as a function of:

temperature

radiation

- measure noise
- output voltage as function of

load/input voltage

DCUs:

 functionality of all DCU ADC channels
 precision of DCU measurements

monitor temperature



ON DETECTOR ELECTRONICS

Modularity: Trigger Tower - it reads a 5x5 grid of crystals:

- + 5 VFEs (Very Front End cards) each one reads a strip of 5 crystals along ϕ
- 1 FE (Front End card) it controls and receives data from the 5 VFEs
- + 1 LVR (Low Voltage Regulator card) it stabilizes and distributes the LV
- 1 MB (Mother Board) it distributes the HV and provides connections to the VFEs. On the FE:
- 2 GOHs (Gigabit Optical Hybrids) to send out data and trigger primitives
- 1 CCU (Clock & Control Unit) I²C interface.

The 68 FEs on a super-module are connected by a system of 8 Token Rings.

OFF DETECTOR ELECTRONICS



Main functions of the off-detector electronic boards:

CCS: reception/distribution of LHC clock and control signals + front-end initialization

- TCC: encoding of trigger primitives and transmission to Regional Calorimeter Trigger at
- 40 MHz + classification of trigger tower importance and transmission to SRP at Level 1 rate
- DCC: integrity check + data reduction + transmission to central DAQ at Level 1 rate





UVa PLANNED STUDIES

- To characterize the DC-DC converters as well as the front end and the assembly performance under temperature, magnetic field and radiation stresses
- To measure the noise generated between the VFE boards

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- To do the temperature tests in the range between 0 and 18 degrees
- The configuration of the Trigger tower and temperature variance environmental box that we need to do 3.8 T test in the UVa superconducting magnet simultaneously with varying the temperature range
- We will follow these tests with some radiation testing most likely at UC Davis, Los Alamos or Sandia Lab
- If needed, we will do temperature torture testing of the Tower electronics assembly
- Finally, we will repeat the desired sequence of test as different versions of the VFE, DC-DC converter and FE card evolve





UVa 3.8 T SUPERCONDUCTING MAGNET





- The UVa's large-bore superconducting magnet is capable of 4.7 T
- Aperture diameter 40 cm
- 20-year-old beast that began its life in the university hospital's MRI lab.
 - for testing vacuum phototriodes (VPTs) (the ECAL endcap photodetector) at <u>various</u> angles in a 3.8 Tesla field
 - Increased range of angle scans from +/- 13° to +/- 25°
 - Using the same amplifiers that comprise the CMS ECAL endcaps for more realistic reproduction of measurement conditions
 - Upgraded from a CAMAC/NIM measurement and timing system to a National Instruments PXI rig with:
 - **FGPA** based Timing control down to 25 ns
 - 2 GHz Digital Scope for precise waveform readout
 - reduced noise
 - Other additions/upgrades
 - Temperature and Humidity Monitoring
 - Amplifier gain monitoring



UVa PRELIMINARY TESTS: SETUP

- UVa's "minimal"setup:
 - I DC-DC converter board
 - 6 DC-DC converter chips (FEASTMP modules)
 - 1 VFE board:
 - board was provided low voltage by the DC-DC converter board with six FEASTMP chips:
 - Five FEASTMP chips were used provided 2.5 V to the VFE board
 - the other FEASTMP chip powered the DC-DC board itself
- GOAL: to measure the noise generated by each of the six DC-DC converter chips on the DC-DC converter board







- The noise from the FEASTMP chips is expected to show up at ~1.8 MHz
- Some <u>"environmental" noise</u>: so compare the spectrum with poweroff to that with only one FEASTMP module at a time plugged in
 Noise from each FEASTMP chip measured with only one of the FEASTMP module in place and powered at a time and compared with the power-off noise spectrum
 Noise spectra measured on the DC power lines leading to the VFE card



Power-off compared to Power-on noise spectrum FEASTMP chip

VFE 1 2.5 V line power on FEAST VFE 1 only



Power-off compared to Power-on noise spectrum FEASTMP chip 2



VFE 2 2.5 V line power on FEAST in VFE 2 slot



Power-off compared to Power-on noise spectrum FEASTMP chip 3

Note: the horizontal scale not quite the same for the power-off and power-on cases. The frequency range of the measurements is from approximately 1.6 to 1.9 MHz.





Power-off compared to Power-on noise spectrum FEASTMP chip 4



VFE 4 2.5 V line power on FEAST in VFE 4 slot

VFE 5 2.5 V line power on FEAST in VFE 5 slot



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Power-off compared to Power-on noise spectrum FEASTMP chip 5

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Power-off compared to Power-on noise spectrum FEASTMP chip 6

VFE 5 2.5 V line, power on "DC-DC" FEAST in VFE 5 slot



FREQUENCY OF THE NOISE PEAKS FROM EACH CHIP		
VFE CHANNEL	FREQUENCY (MHz)	
VFE 1	1.719	
VFE 2	1.845	
VFE 3	1.735	
VFE 4	1.848	
VFE 5	1.795	
DC-DC BOARD	1.821	

All 6 DC-DC converter chips have slightly different frequencies, close to but significantly different from 1.8 MHz.

One of the chips generated larger noise on the power lines than the other five.
 As well as measuring the noise on the DC lines, we have tried to measure the resulting noise on the VFE card at a point between the amplifier chips and the ADC chip → not able to detect any noise signal at the frequency of the FEASTMP noise to date

NOISE PEAK: DIFFERENCES wrt THE LOAD FROM THE VFE CARD

Is the noise peak different with the load imposed by the VFE card?
Power-on vs. power-off measurements were made on the power lines for load and no-load and for each FEASTMP chip.
The arrows show the positions of the noise peaks from the FEASTMP chips

VFE 1 with load A COM N N 9 N Vous and a second and a second as a 1.75 MHz 1.8 MHz 1.85 MHz

No VFE load is compared to VFE loaded noise spectrum FEASTMP chip 1

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VFE 1 without load

No VFE load is compared to VFE loaded noise spectrum FEASTMP chip 2

VFE 3 no load



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No VFE load is compared to VFE loaded noise sspectrum FEASTMP chip 3

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No VFE load is compared to VFE loaded noise spectrum FEASTMP chip 4



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No VFE load is compared to VFE loaded noise spectrum FEASTMP chip 5

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No DC-DC load is compared to DC-DC loaded noise spectrum

"DC-DC" no load



The effect of applying the VFE load seems to decrease significantly the observed noise on two of the power lines but leave the noise unchanged on the remaining four

We will need to fully load the mother board with VFE cards to get a better sense of what is going on → for these tests we only had one VFE card

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Possible existence of cross talk: does the noise show up on the other 2.5V lines when all the FEASTMP chips are plugged in?

This was investigated by measuring the noise on lines other than the ones that are powered by each individual FEASTMP chip.

VFE 1 2.5V line power on no load (i.e. no VFE card in any slot)

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VFE 2 2.5V line power on no load

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VFE 3 2.5V line power on no load

VFE 4 2.5V line power on no load



VFE 5 2.5V line power on no load

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VFE 2 2.5V line power on VFE card in VFE 2 slot

VFE 3 2.5 V line power on VFE card in VFE 3 slot



VFE 4 2.5V line power on VFE card in VFE 4 slot

VFE 5 2.5V line power on VFE card in VFE 5 slot



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WHAT IS ONGOING

Built one complete Trigger Tower Test setup, (the basic element of the front end system)



We got Trigger Tower powered up

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At 12 Volts input it draws about 3 amps from the power supply

The current card with the FEASTMP modules turns the FEASTMP's on as soon as they are powered

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WHAT IS ONGOING

Started to think about how to readout it using the GLIB card

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WHAT WE STILL NEED TO READOUT

- Still some missing pieces that we need to readout the TT using a GLIB card (the optical fiber cable and the mezzanine card to communicate with the GLIB)
 - I aluminum cooling plate for the VFE card that doesn't have one
 - better we get another VFE card with the housing already attached otherwise we will also need the gap-filling material
 - one or two GOH cards, the optical transmitter that plugs into the FE card
 - on problems with GOH and MU-MPO adapters
 - No single DOH available
 - the rest of the cooling blocks for the 5 by 5 TT setup that maybe we can get from CERN (we need to check if it fits in the UVa's magnet)
 - it seems there are 4 pieces of Endocarps cooling blocks but maybe there are not leak tight (maybe we can use Peltier cooler)
 - Iong optical fiber (about 5 meters) or at least the specifics so we can make one by ourselves

We also need to know what are using at CERN in the test setup for the trigger and slow control and readout through the token ring



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CONCLUSIONS

Started to arrange a more complete and realistic system as the Trigger Tower Test setup

We still need some suggestions in order to readout using the GLIB card

We aim to be able to conduct tests at the 0.1% level of the effects of noise as a function of temperature variation, 3.8 magnetic fields, and a set of radiation tests at the level expect for 3000 fb⁻¹ behind the lead tungstate (PbWO₄) crystals
 First tests with "minimal setup" shown:

all 6 DC-DC converter chips have slightly different frequencies, close to but significantly different from 1.8 MHz

one of the chips generated larger noise on the power lines than the other five
 investigating the noise peak difference with the load imposed by the VFE card we realized that the is effect seems to decrease significantly the observed noise on two of the power lines but leave the noise unchanged on the remaining four
 we also tried to test the possibility of cross-talk by measuring the noise on lines other than the ones that are powered by each individual FEAST chip



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BACKUP



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